

# **AOS Semiconductor**

## **Product Reliability Report**

**AO7410/AO7410L, rev A**

**Plastic Encapsulated Device**

**ALPHA & OMEGA Semiconductor, Inc**

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This AOS product reliability report summarizes the qualification result for AO7410. Accelerated environmental tests are performed on a specific sample size, and then followed by electrical test at end point. Review of final electrical test result confirms that AO7410 passes AOS quality and reliability requirements. The released product will be categorized by the process family and be monitored on a quarterly basis for continuously improving the product quality.

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### I. Product Description:

The AO7410 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , very low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a load switch or in PWM applications. AO7410L (Green Product) is offered in a lead-free package.

Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted				
Parameter		Symbol	Maximum	Units
Drain-Source Voltage		$V_{DS}$	30	V
Gate-Source Voltage		$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>A</sup>	$T_A=25^\circ\text{C}$	$I_D$	1.6	A
	$T_A=70^\circ\text{C}$		1.3	
Pulsed Drain Current <sup>B</sup>		$I_{DM}$	10	
Power Dissipation <sup>A</sup>	$T_A=25^\circ\text{C}$	$P_D$	0.35	W
	$T_A=70^\circ\text{C}$		0.22	
Junction and Storage Temperature Range		$T_J, T_{STG}$	-55 to 150	$^\circ\text{C}$

Thermal Characteristics					
Parameter		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient	$T = 10\text{s}$	$R_{\theta JA}$	300	360	$^\circ\text{C/W}$
	Steady-State		340	425	
Maximum Junction-to-Lead	Steady-State	$R_{\theta JL}$	280	320	

## II. Die / Package Information:

	<b>AO7410</b>	<b>AO7410L (Green Compound)</b>
<b>Process</b>	Standard sub-micron low voltage N channel process	Standard sub-micron low voltage N channel process
<b>Package Type</b>	SC-70 3L	SC-70 3L
<b>Lead Frame</b>	Alloy 42 Ag spot	Alloy 42 Ag spot
<b>Die Attach</b>	Silver epoxy	Silver epoxy
<b>Bondwire</b>	1.3 mils Au wire	1.3 mils Au wire
<b>Mold Material</b>	Epoxy resin with silica filler	Epoxy resin with silica filler
<b>Filler % (Spherical/Flake)</b>	50/50	100/0
<b>Flammability Rating</b>	UL-94 V-0	UL-94 V-0
<b>Backside Metallization</b>	Ti / Ni / Ag	Ti / Ni / Ag
<b>Moisture Level</b>	Up to Level 1 *	Up to Level 1*

**Note \*** based on info provided by assembler and mold compound supplier

## III. Result of Reliability Stress for AO7410 (Standard) & AO7410L (Green)

Test Item	Test Condition	Time Point	Lot Attribution	Total Sample size	Number of Failures
<b>Solder Reflow Precondition</b>	Normal: 1hr PCT+3 cycle IR reflow @240 °c (260° c for Green)	0hr	Normal: 9 lots Green: 3 lots	1760 pcs	0
<b>HTGB</b>	Temp = 150 C, Vgs=100% of Vgsmx	168 / 500 hrs  1000 hrs	Normal: 2 lots Green: 1 lot  (Note A*)	246 pcs  77+5 pcs / lot	0
<b>HTRB</b>	Temp = 150 C, Vds=80% of Vdsmax	168 / 500 hrs  1000 hrs	Normal: 2 lots Green: 1 lot  (Note A*)	246 pcs  77+5 pcs / lot	0
<b>HAST</b>	130 +/- 2 C, 85%, 33.3 psi, Vgs = 80% of Vgs max	100 hrs	Normal: 5 lots Green: 3 lots  (Note B**)	440 pcs  50+5 pcs / lot	0
<b>Pressure Pot</b>	121 C, 15+/-1 PSIG, RH=100%	96 hrs	Normal: 9 lots Green: 3 lots  (Note B**)	660 pcs  50+5 pcs / lot	0
<b>Temperature Cycle</b>	-65 to 150 deg C, air to air, 0.5hr per cycle	250 / 500 cycles	Normal: 9 lots Green: 3 lots  (Note B**)	660 pcs  50+5 pcs / lot	0
<b>DPA</b>	Internal Vision Cross-section X-ray	NA	5 5 5	5 5 5	0
<b>CSAM</b>		NA	5	5	0

<b>Bond Integrity</b>	Room Temp 150° C bake 150° C bake	0hr 250hr 500hr	40 40 40	40 wires 40 wires 40 wires	0
<b>Solderability</b>	230° C	5 sec	15	15 leads	0
<b>Die shear</b>	150° C	0hr	10	10	0

**Note A:** The HTGB and HTRB reliability data presents total of available AO7410 and **AO7410L** burn-in data up to the published date.

**Note B:** The pressure pot, temperature cycle and HAST reliability data for **AO7410L** comes from the AOS generic green compound package qualification data.

#### IV. Reliability Evaluation

**FIT rate (per billion): 21.3**

**MTBF = 5342 years**

500 hrs of HTGB, 150 deg C accelerated stress testing is equivalent to 15 years of lifetime at 55 deg C operating conditions (by applying the Arrhenius equation with an activation energy of 0.7eV and 60% of upper confidence level on the failure rate calculation). AOS reliability group also routinely monitors the product reliability up to 1000 hr at and performs the necessary failure analysis on the units failed for reliability test(s).

The presentation of FIT rate for the individual product reliability is restricted by the actual burn-in sample size of the selected product (AO7410). Failure Rate Determination is based on JEDEC Standard JESD 85. FIT means one failure per billion hours.

$$\text{Failure Rate} = \text{Chi}^2 \times 10^9 / [2 (N) (H) (Af)] = 1.83 \times 10^9 / [2 (164) (1000) (258.24)] = 21.3$$

$$\text{MTBF} = 10^9 / \text{FIT} = 4.68 \times 10^7 \text{ hrs} = 5342 \text{ years}$$

**Chi<sup>2</sup>** = Chi Squared Distribution, determined by the number of failures and confidence interval

**N** = Total Number of units from HTRB and HTGB tests

**H** = Duration of HTRB/HTGB testing

**Af** = Acceleration Factor from Test to Use Conditions (Ea = 0.7eV and Tuse = 55C)

Acceleration Factor [**Af**] =  $\text{Exp} [Ea / k (1/Tj u - 1/Tj s)]$

**Acceleration Factor ratio list:**

	55 deg C	70 deg C	85 deg C	100 deg C	115 deg C	130 deg C	150 deg C
<b>Af</b>	<b>258</b>	<b>87</b>	<b>32</b>	<b>13</b>	<b>5.64</b>	<b>2.59</b>	<b>1</b>

**Tj s** = Stressed junction temperature in degree (Kelvin), K = C+273.16

**Tj u** = The use junction temperature in degree (Kelvin), K = C+273.16

**k** = Boltzman's constant, 8.617164 X 10E -5eV / K



## V. Quality Assurance Information

Acceptable Quality Level for outgoing inspection: **0.1%** for electrical and visual.

Guaranteed Outgoing Defect Rate: **< 25 ppm**

Quality Sample Plan: conform to **Mil-Std-105D**

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